

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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on re the Application of: H. WATANABE et al.

Serial No.: 09/320,271

Group Art Unit: 2825

Filed: May 27, 1999

Examiner: C. Lee

For: SEMICONDUCTOR DEVICE AND FABRICATION METHOD THEREOF

PRELIMINARY AMENDMENT

Commissioner for Patents Washington, D.C. 20231

Date: May 14, 2001

Sir:

Prior to continued examination, please amend the above-identified application as follows:

IN THE CLAIMS:

Please amend claim 1 as follows:

1. (Amended) A fabrication method of a semiconductor device comprising the steps

of:

forming a first insulation layer over a substrate,

introducing impurities into said first insulation layer, and

embedding and forming a first conductive layer in said first insulation layer.

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